

Notice of References Cited	Application/Control No. 10/655,900	Applicant(s)/Patent Under Reexamination SHIUE ET AL.	
	Examiner Sayed T. Zewari	Art Unit 2687	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,934,568	08-2005	Charlier et al.	455/575.3
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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